8-bit addressable latch Rev. 02 — 15 May 2008

Product data sheet

1. General description

The 74AHC259; 74AHCT259 is a high-speed Si-gate CMOS device and is pin compatible with Low-power Schottky TTL (LSTTL). It is specified in compliance with JEDEC standard No. 7-A.

The 74AHC259; 74AHCT259 is a high-speed 8-bit addressable latch designed for general purpose storage applications in digital systems. It is a multifunctional device capable of storing single-line data in eight addressable latches and providing a 3-to-8 decoder and multiplexer function with active HIGH outputs (Q0 to Q7). It also incorporates an active LOW common reset ($\overline{\text{MR}}$) for resetting all latches as well as an active LOW enable input ($\overline{\text{LE}}$).

The 74AHC259; 74AHCT259 has four modes of operation:

- In the addressable latch mode, data on the data line (D) is written into the addressed latch. The addressed latch will follow the data input with all non-addressed latches remaining in their previous states.
- In the memory mode, all latches remain in their previous states and are unaffected by the data or address inputs.
- In the 3-to-8 decoding or demultiplexing mode, the addressed output follows the state of the data input (D) with all other outputs in the LOW state.
- In the reset mode, all outputs are LOW and unaffected by the address inputs (A0 to A2) and data input (D).

When operating the 74AHC259; 74AHCT259 as an address latch, changing more than one bit of the address could impose a transient-wrong address. Therefore, this should only be done while in the memory mode.

2. Features

- Balanced propagation delays
- All inputs have Schmitt-trigger actions
- Combines demultiplexer and 8-bit latch
- Serial-to-parallel capability
- Output from each storage bit available
- Random (addressable) data entry
- Easily expandable
- Common reset input
- Useful as a 3-to-8 active HIGH decoder
- Inputs accept voltages higher than V_{CC}



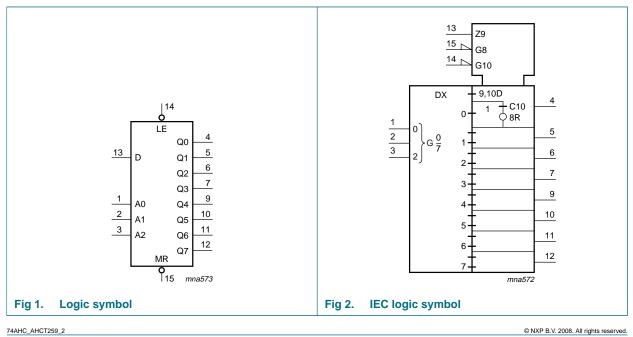
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- Input levels:
 - ◆ For 74AHC259: CMOS level
 - For 74AHCT259: TTL level
- ESD protection:
 - ◆ HBM EIA/JESD22-A114E exceeds 2000 V
 - MM EIA/JESD22-A115-A exceeds 200 V
 - CDM EIA/JESD22-C101C exceeds 1000 V
- Multiple package options
- Specified from -40 °C to +85 °C and from -40 °C to +125 °C

3. Ordering information

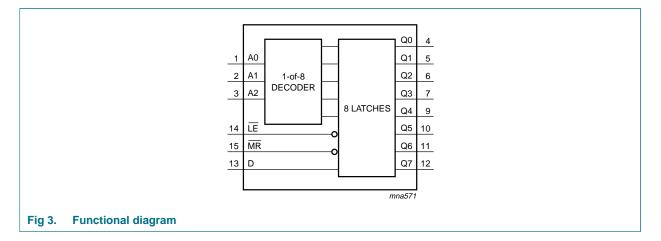
Table 1. Order	ring information			
Type number	Package			
	Temperature range	Name	Description	Version
74AHC259				
74AHC259D	–40 °C to +125 °C	SO16	plastic small outline package; 16 leads; body width 3.9 mm	SOT109-1
74AHC259PW	–40 °C to +125 °C	TSSOP16	plastic thin shrink small outline package; 16 leads; body width 4.4 mm	SOT403-1
74AHCT259				
74AHCT259D	–40 °C to +125 °C	SO16	plastic small outline package; 16 leads; body width 3.9 mm	SOT109-1
74AHCT259PW	–40 °C to +125 °C	TSSOP16	plastic thin shrink small outline package; 16 leads; body width 4.4 mm	SOT403-1

4. Functional diagram



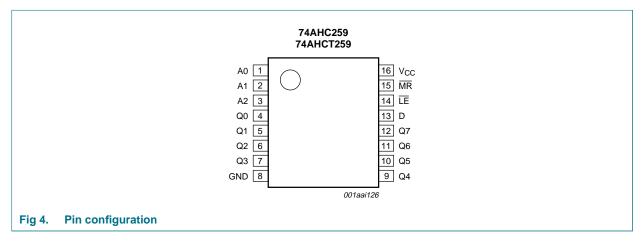
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5. Pinning information

5.1 Pinning



5.2 Pin description

Table 2.	Pin description		
Symbol	Pin	Description	
A0	1	address input	
A1	2	address input	
A2	3	address input	
Q0	4	latch output	
Q1	5	latch output	
Q2	6	latch output	
Q3	7	latch output	
GND	8	ground (0 V)	
Q4	9	latch output	
Q5	10	latch output	
74AHC_AHCT259	_2		© NXP B.V. 2008. All rights reserved.
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Table 2.	Pin description	.continued
Symbol	Pin	Description
Q6	11	latch output
Q7	12	latch output
D	13	data input
ΙĒ	14	latch enable input (active LOW)
MR	15	conditional reset input (active LOW)
V _{CC}	16	supply voltage

6. Functional description

Table 3. Function table^[1]

Operating mode	Inpu	it					Outpu	ıt						
	MR	LE	D	A0	A1	A2	Q0	Q1	Q2	Q3	Q4	Q5	Q6	Q7
Reset (clear)	L	Н	Х	Х	Х	Х	L	L	L	L	L	L	L	L
Demultiplexer	L	L	d	L	L	L	Q = d	L	L	L	L	L	L	L
(active HIGH 8-channel) decoder (when D = H)			d	Н	L	L	L	Q = d	L	L	L	L	L	L
			d	L	Н	L	L	L	Q = d	L	L	L	L	L
			d	Н	Н	L	L	L	L	Q = d	L	L	L	L
			d	L	L	Н	L	L	L	L	Q = d	L	L	L
			d	Н	L	Н	L	L	L	L	L	Q = d	L	L
			d	L	Н	Н	L	L	L	L	L	L	Q = d	L
			d	Н	Н	Н	L	L	L	L	L	L	L	Q = d
Memory (no action)	Н	Н	Х	Х	Х	Х	q 0	q ₁	q ₂	q ₃	q ₄	q 5	q ₆	q ₇
Addressable latch	Н	L	d	L	L	L	Q = d	q ₁	q ₂	q ₃	q ₄	q 5	q ₆	q ₇
			d	Н	L	L	q 0	Q = d	q ₂	q ₃	q ₄	q 5	q ₆	q ₇
			d	L	Н	L	q 0	q ₁	Q = d	q ₃	q ₄	q 5	q ₆	q ₇
			d	Н	Н	L	q 0	q 1	q ₂	Q = d	q ₄	q ₅	q ₆	q ₇
			d	L	L	Н	q 0	q ₁	q ₂	q ₃	Q = d	q 5	q ₆	q ₇
			d	Н	L	Н	q 0	q ₁	q ₂	q ₃	q ₄	Q = d	q ₆	q ₇
			d	L	Н	Н	q 0	q ₁	q ₂	q ₃	q ₄	q 5	Q = d	q ₇
			Н	Н	Н	Н	q 0	q ₁	q ₂	q ₃	q ₄	q 5	q ₆	Q = d

[1] H = HIGH voltage level;

L = LOW voltage level;

X = don't care;

d = HIGH or LOW data one set-up time prior to the LOW-to-HIGH \overline{LE} transition;

q = lower case letter indicates the state of the referenced input one set-up time prior to the LOW-to-HIGH transition.

Table 4.	Operating mode sele	ct table[1]
LE	MR	Mode
L	Н	addressable latch
Н	Н	memory
L	L	active HIGH 8-channel demultiplexer
Н	L	reset

[1] H = HIGH voltage level; L = LOW voltage level.

7. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		-0.5	+7.0	V
VI	input voltage		-0.5	+7.0	V
I _{IK}	input clamping current	V _I < -0.5 V	<u>[1]</u> –20	-	mA
I _{OK}	output clamping current	V_O < –0.5 V or V_O > V_{CC} + 0.5 V	<u>[1]</u> –20	+20	mA
lo	output current	$V_{\rm O}$ = –0.5 V to (V_{\rm CC} + 0.5 V)	-25	+25	mA
I _{CC}	supply current		-	+75	mA
I _{GND}	ground current		-75	-	mA
T _{stg}	storage temperature		-65	+150	°C
P _{tot}	total power dissipation	$T_{amb} = -40 \ ^{\circ}C \ to +125 \ ^{\circ}C$	[2] _	500	mW

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

8. Recommended operating conditions

Table 6. Operating conditions

	operating contaitions					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
74AHC25	59					
V _{CC}	supply voltage		2.0	5.0	5.5	V
VI	input voltage		0	-	5.5	V
Vo	output voltage		0	-	V _{CC}	V
T _{amb}	ambient temperature		-40	+25	+125	°C
Δt/ΔV	input transition rise and fall rate	V_{CC} = 3.0 V to 3.6 V	-	-	100	ns/V
		V_{CC} = 4.5 V to 5.5 V	-	-	20	ns/V
74AHCT2	259					
V _{CC}	supply voltage		4.5	5.0	5.5	V
VI	input voltage		0	-	5.5	V
Vo	output voltage		0	-	V _{CC}	V
T _{amb}	ambient temperature		-40	+25	+125	°C
$\Delta t / \Delta V$	input transition rise and fall rate	$V_{CC} = 4.5 \text{ V} \text{ to } 5.5 \text{ V}$	-	-	20	ns/V

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9. Static characteristics

Table 7. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C		−40 °C t	o +85 °C	–40 °C to +125 °C		Uni
			Min	Тур	Max	Min	Max	Min	Max	
74AHC2	59									
VIH	HIGH-level	V _{CC} = 2.0 V	1.5	-	-	1.5	-	1.5	-	V
	input voltage	V _{CC} = 3.0 V	2.1	-	-	2.1	-	2.1	-	V
		V _{CC} = 5.5 V	3.85	-	-	3.85	-	3.85	-	V
VIL	LOW-level	V _{CC} = 2.0 V	-	-	0.5	-	0.5	-	0.5	V
	input voltage	V _{CC} = 3.0 V	-	-	0.9	-	0.9	-	0.9	V
		V _{CC} = 5.5 V	-	-	1.65	-	1.65	-	1.65	V
V _{OH}	HIGH-level	$V_{I} = V_{IH} \text{ or } V_{IL}$								
	output voltage	$I_{O} = -50 \ \mu A; \ V_{CC} = 2.0 \ V$	1.9	2.0	-	1.9	-	1.9	-	V
		$I_{O} = -50 \ \mu A; \ V_{CC} = 3.0 \ V$	2.9	3.0	-	2.9	-	2.9	-	V
		$I_{O} = -50 \ \mu A; V_{CC} = 4.5 \ V$	4.4	4.5	-	4.4	-	4.4	-	V
		$I_{O} = -4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	2.58	-	-	2.48	-	2.40	-	V
		$I_{O} = -8.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	3.94	-	-	3.80	-	3.70	-	V
V _{OL}	LOW-level	$V_{I} = V_{IH} \text{ or } V_{IL}$								
	output voltage	$I_0 = 50 \ \mu A; V_{CC} = 2.0 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_0 = 50 \ \mu A; V_{CC} = 3.0 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_0 = 50 \ \mu A; V_{CC} = 4.5 \ V$	-	0	0.1	-	0.1	-	0.1	V
		I _O = 4.0 mA; V _{CC} = 3.0 V	-	-	0.36	-	0.44	-	0.55	V
		I_{O} = 8.0 mA; V_{CC} = 4.5 V	-	-	0.36	-	0.44	-	0.55	V
I	input leakage current	$V_{I} = 5.5 V \text{ or GND};$ $V_{CC} = 0 V \text{ to } 5.5 V$	-	-	0.1	-	1.0	-	2.0	μΑ
l _{cc}	supply current		-	-	4.0	-	40	-	80	μΑ
Cı	input capacitance	$V_{I} = V_{CC}$ or GND	-	3	10	-	10	-	10	pF
Co	output capacitance		-	4	-	-	-	-	-	pF
74АНСТ	259									
V _{IH}	HIGH-level input voltage	V_{CC} = 4.5 V to 5.5 V	2.0	-	-	2.0	-	2.0	-	V
V _{IL}	LOW-level input voltage	V_{CC} = 4.5 V to 5.5 V	-	-	0.8	-	0.8	-	0.8	V
√ _{ОН}	HIGH-level	$V_{I} = V_{IH} \text{ or } V_{IL}; V_{CC} = 4.5 \text{ V}$								
	output voltage	I _O = -50 μA	4.4	4.5	-	4.4	-	4.4	-	V
		I _O = -8.0 mA	3.94	-	-	3.80	-	3.70	-	V
V _{OL}	LOW-level	$V_{I} = V_{IH} \text{ or } V_{IL}; V_{CC} = 4.5 \text{ V}$								
	output voltage	I _O = 50 μA	-	0	0.1	-	0.1	-	0.1	V
		l _O = 8.0 mA	-	-	0.36	-	0.44	-	0.55	V

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Symbol	Parameter	Conditions		25 °C		–40 °C to	o +85 °C	–40 °C to +125 °C		Unit
			Min	Тур	Max	Min	Max	Min	Max	
l _l	input leakage current	V _I = 5.5 V or GND; V _{CC} = 0 V to 5.5 V	-	-	0.1	-	1.0	-	2.0	μA
I _{CC}	supply current	$\label{eq:VI} \begin{array}{l} V_{I} = V_{CC} \text{ or } GND; \ I_{O} = 0 \ A; \\ V_{CC} = 5.5 \ V \end{array}$	-	-	4.0	-	40	-	80	μA
ΔI_{CC}	additional supply current	per input pin; V _I = V _{CC} - 2.1 V; other pins at V _{CC} or GND; $I_O = 0 A$; V _{CC} = 4.5 V to 5.5 V	-	-	1.35	-	1.5	-	1.5	mA
CI	input capacitance	$V_I = V_{CC}$ or GND	-	3	10	-	10	-	10	pF
Co	output capacitance		-	4	-	-	-	-	-	pF

Table 7. Static characteristics ...continued

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

10. Dynamic characteristics

Table 8. Dynamic characteristics

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 11.

0											
Symbol	Parameter	Conditions			25 °C		–40 °C t	o +85 °C	–40 °C to	o +125 °C	Unit
				Min	Typ <mark>[1]</mark>	Max	Min	Max	Min	Max	
74AHC2	59										
t _{pd}		D to Qn; see Figure 5	[2]								
	delay	V_{CC} = 3.0 V to 3.6 V									
		C _L = 15 pF		-	5.8	11.5	1.0	13.5	1.0	15.0	ns
		C _L = 50 pF		-	7.3	14.5	1.0	17.0	1.0	18.5	ns
		V_{CC} = 4.5 V to 5.5 V									
		C _L = 15 pF		-	4.1	7.5	1.0	9.0	1.0	10.0	ns
		C _L = 50 pF		-	5.3	9.5	1.0	11.0	1.0	12.0	ns
		An to Qn; see Figure 6	[2]								
		V_{CC} = 3.0 V to 3.6 V									
		C _L = 15 pF		-	7.5	14.5	1.0	17.0	1.0	18.5	ns
		C _L = 50 pF		-	9.1	18.0	1.0	21.0	1.0	23.0	ns
		V_{CC} = 4.5 V to 5.5 V									
		C _L = 15 pF		-	5.3	9.5	1.0	11.5	1.0	12.5	ns
		C _L = 50 pF		-	6.5	11.5	1.0	13.5	1.0	15.0	ns
		LE to Qn; see Figure 7	[2]								
		V_{CC} = 3.0 V to 3.6 V									
		C _L = 15 pF		-	6.2	12.0	1.0	14.0	1.0	15.2	ns
		C _L = 50 pF		-	7.7	15.5	1.0	17.5	1.0	19.0	ns
		V_{CC} = 4.5 V to 5.5 V									
		C _L = 15 pF		-	4.3	8.0	1.0	9.5	1.0	10.5	ns
		C _L = 50 pF		-	5.5	10.0	1.0	11.5	1.0	12.5	ns

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Symbol	Parameter	Conditions			25 °C		-40 °C ∙	to +85 °C	-40 °C to	o +125 °C	Uni
				Min	Typ <mark>[1]</mark>	Max	Min	Max	Min	Max	1
t _{pd}	propagation	MR to Qn; see Figure 8	[3]								
	delay	V _{CC} = 3.0 V to 3.6 V									
		C _L = 15 pF		-	5.4	10.5	1.0	12.5	1.0	13.5	ns
		C _L = 50 pF		-	7.0	13.5	1.0	15.5	1.0	17.0	ns
		V_{CC} = 4.5 V to 5.5 V									
		C _L = 15 pF		-	3.9	7.0	1.0	8.5	1.0	9.5	ns
		C _L = 50 pF		-	5.1	9.0	1.0	10.5	1.0	11.5	ns
t _W	pulse width	LE HIGH or LOW; see Figure 7									
		V_{CC} = 3.0 V to 3.6 V		5.0	-	-	5.0	-	5.0	-	ns
		V_{CC} = 4.5 V to 5.5 V		5.0	-	-	5.0	-	5.0	-	ns
		MR LOW; see Figure 8									
		V_{CC} = 3.0 V to 3.6 V		5.0	-	-	5.0	-	5.0	-	ns
		V_{CC} = 4.5 V to 5.5 V		5.0	-	-	5.0	-	5.0	-	ns
t _{su}	set-up time	D, An to $\overline{\text{LE}}$; see Figure 9 and Figure 10									
		V_{CC} = 3.0 V to 3.6 V		4.0	-	-	4.0	-	4.0	-	ns
		V_{CC} = 4.5 V to 5.5 V		4.0	-	-	4.0	-	4.0	-	ns
t _h	hold time	D, An to $\overline{\text{LE}}$; see Figure 9 and Figure 10									
		V_{CC} = 3.0 V to 3.6 V		1.0	-	-	1.0	-	1.0	-	ns
		V_{CC} = 4.5 V to 5.5 V		1.0	-	-	1.0	-	1.0	-	ns
C _{PD}	power dissipation capacitance	$f_i = 1 \text{ MHz}; V_I = \text{GND to } V_{\text{CC}}$	<u>[4]</u>	-	13	-	-	-	-	-	рF
74AHCT	259; V _{CC} = 4.	5 V to 5.5 V									
t _{pd}		D to Qn; see Figure 5	[2]								
	delay	C _L = 15 pF		-	4.1	7.5	1.0	9.0	1.0	10.0	ns
		C _L = 50 pF		-	5.4	9.5	1.0	11.0	1.0	12.0	ns
		An to Qn; see Figure 6	[2]								
		C _L = 15 pF		-	5.5	9.5	1.0	11.5	1.0	12.5	ns
		C _L = 50 pF		-	6.6	12.0	1.0	14.0	1.0	15.5	ns
		LE to Qn; see Figure 7	[2]								
		C _L = 15 pF		-	4.3	8.0	1.0	9.5	1.0	10.4	ns
		C _L = 50 pF		-	5.5	10.0	1.0	12.0	1.0	13.0	ns
		MR to Qn; see Figure 8	[3]								
		C _L = 15 pF		-	3.9	7.0	1.0	8.5	1.0	9.5	ns
		C _L = 50 pF		-	5.1	9.0	1.0	10.5	1.0	11.5	ns
t _W	pulse width	LE HIGH or LOW; see Figure 7		5.0	-	-	5.0	-	5.0	-	ns
		MR LOW; see Figure 8		5.0	-	-	5.0	-	5.0	-	ns
4AHC_AHCT2	59.2								© NY	9 B.V. 2008. All rig	hts rer

 Table 8.
 Dynamic characteristics ...continued

 Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 11.

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Symbol	Parameter	Conditions		25 °C		–40 °C t	o +85 °C	–40 °C to	o +125 °C	Unit
			Min	Typ[1]	Max	Min	Max	Min	Max	
t _{su}	set-up time	D, An to LE; see <u>Figure 9</u> and <u>Figure 10</u>	4.0	-	-	4.0	-	4.0	-	ns
t _h	hold time	D, An to LE; see <u>Figure 9</u> and <u>Figure 10</u>	1.0	-	-	1.0	-	1.0	-	ns
C _{PD}	power dissipation capacitance	$f_i = 1 \text{ MHz}; V_I = \text{GND to } V_{\text{CC}}$] -	17	-	-	-	-	-	pF

Table 8. Dynamic characteristics ...continued

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 11.

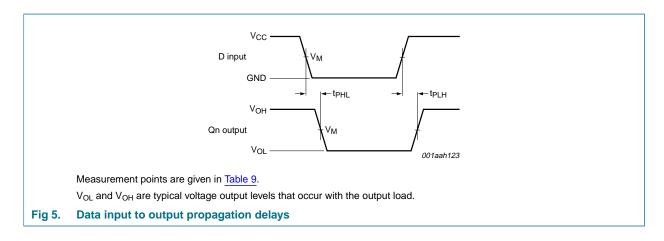
[1] Typical values are measured at nominal supply voltage (V_{CC} = 3.3 V and V_{CC} = 5.0 V).

- [2] t_{pd} is the same as t_{PLH} and t_{PHL} .
- [3] t_{pd} is the same as t_{PHL} only.
- [4] C_{PD} is used to determine the dynamic power dissipation (P_D in μ W).
 - $\mathsf{P}_{\mathsf{D}} = \mathsf{C}_{\mathsf{PD}} \times \mathsf{V}_{\mathsf{CC}}^2 \times \mathsf{f}_i \times \mathsf{N} + \Sigma(\mathsf{C}_{\mathsf{L}} \times \mathsf{V}_{\mathsf{CC}}^2 \times \mathsf{f}_o) \text{ where:}$
 - f_i = input frequency in MHz;
 - $f_o = output frequency in MHz;$
 - C_L = output load capacitance in pF;
 - V_{CC} = supply voltage in V;

N = number of inputs switching;

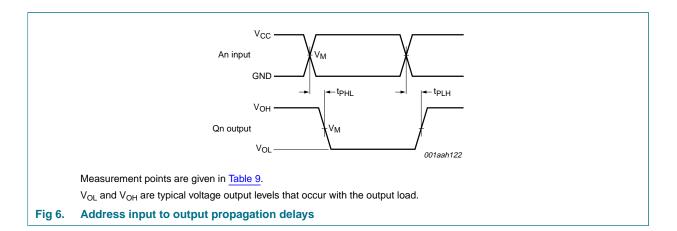
 $\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs.

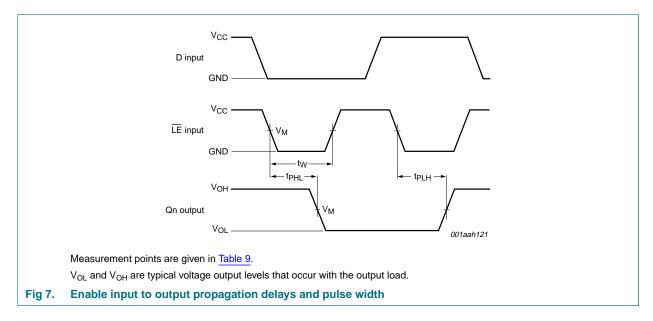
11. Waveforms

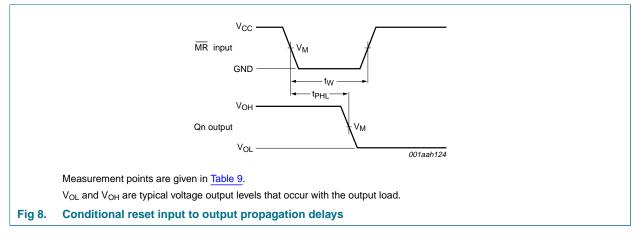


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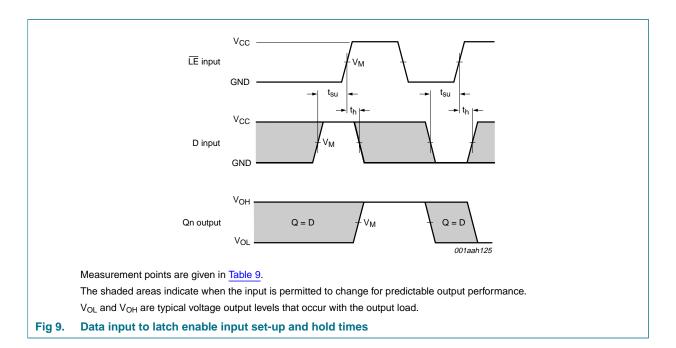




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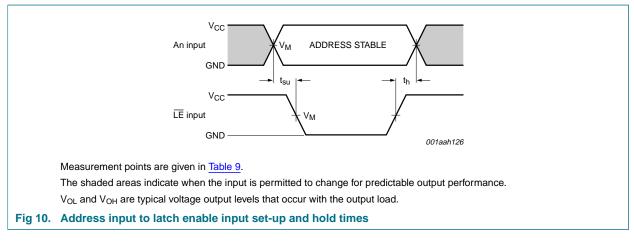


Table 9. Measurement points

Туре	Input	Output
	V _M	V _M
74AHC259	$0.5 \times V_{CC}$	$0.5 \times V_{CC}$
74AHCT259	1.5 V	$0.5 imes V_{CC}$

74AHC259; 74AHCT259

8-bit addressable latch

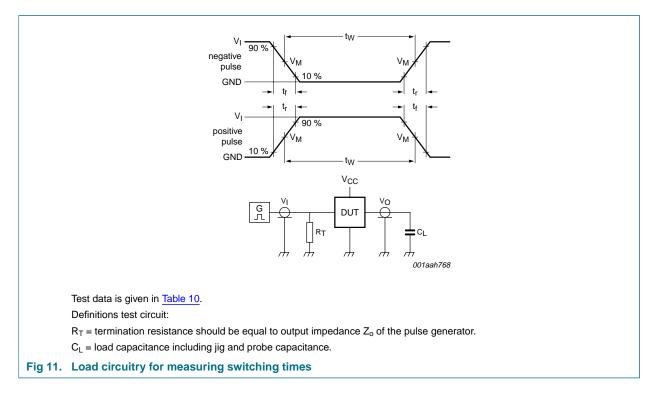


Table 10. Test data

Туре	Input		Load	Test
	VI	t _r , t _f	CL	
74AHC259	V _{CC}	≤ 3.0 ns	15 pF, 50 pF	t _{PLH} , t _{PHL}
74AHCT259	3.0 V	≤ 3.0 ns	15 pF, 50 pF	t _{PLH} , t _{PHL}

8-bit addressable latch

12. Package outline

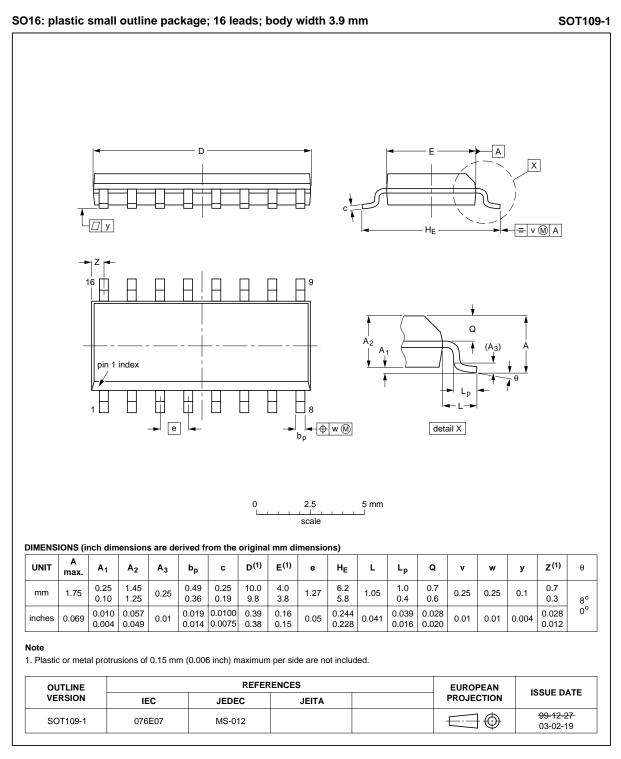


Fig 12. Package outline SOT109-1 (SO16)

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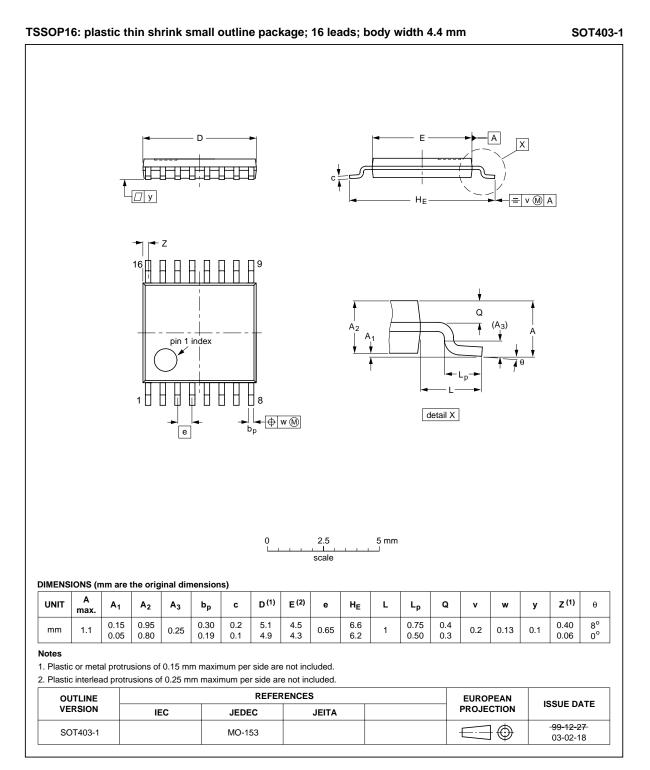


Fig 13. Package outline SOT403-1 (TSSOP16)

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13. Abbreviations

Table 11.	Abbreviations
Acronym	Description
CDM	Charged Device Model
CMOS	Complementary Metal-Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
LSTTL	Low-power Schottky Transistor-Transistor Logic
MM	Machine Model

14. Revision history

Table 12. Revision h	istory				
Document ID	Release date	Data sheet status	Change notice	Supersedes	
74AHC_AHCT259_2	20080515	Product data sheet	-	74AHC_AHCT259_1	
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 				
	 Legal texts have been adapted to the new company name where appropriate. 				
	 <u>Table 6</u>: the conditions for input leakage current have been changed. 				
74AHC_AHCT259_1	20000314	Product specification	-	-	

15. Legal information

15.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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